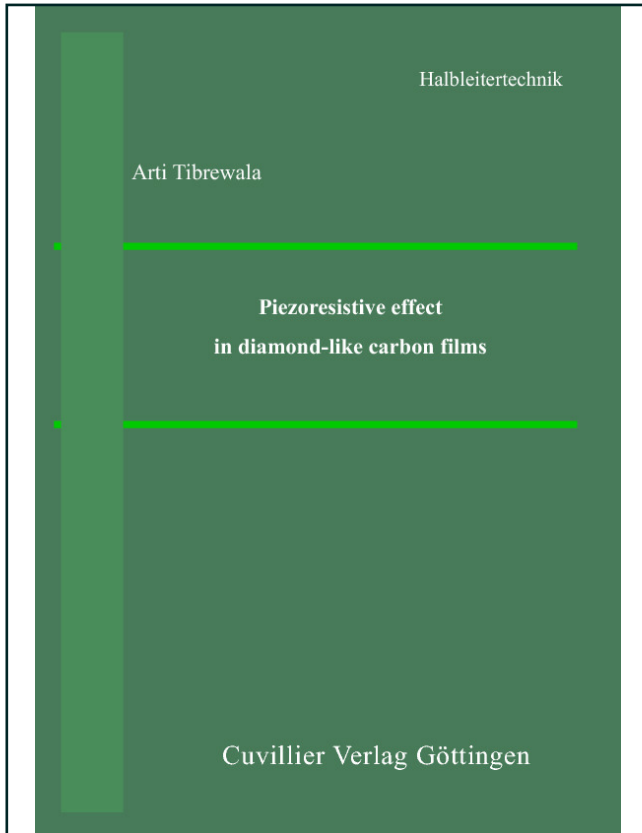




Arti Tibrewala (Autor)

Piezoresistive effect in diamond-like carbon films



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Telefon: +49 (0)551 54724-0, E-Mail: info@cuvillier.de, Website: <https://cuvillier.de>

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